

Resource Summary Report

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Zeiss Xradia 620 Versa X-ray microscope

RRID:SCR_028320

Type: Tool

Proper Citation

Zeiss Xradia 620 Versa X-ray microscope (RRID:SCR_028320)

Resource Information

URL: <https://pdf.directindustry.com/viewerCatalog/zeiss-metrologie-et-microscopie-industrielle/zeiss-xradia-versa-family/210459-1006465.html#open>

Proper Citation: Zeiss Xradia 620 Versa X-ray microscope (RRID:SCR_028320)

Description: High-resolution 3D X-ray microscope (micro-CT) designed for non-destructive, submicron imaging of internal structures in materials science, electronics, and life sciences. It allows researchers to visualize 3D details at 500 nm resolution without cutting samples, using "Resolution at a Distance" (RaaD™) technology to image large or complex items.

Synonyms: ZEISS Xradia 620 Versa

Resource Type: instrument resource

Keywords: ABRF, 3D X-ray microscope, micro-CT, non-destructive, submicron, imaging, materials internal structures,

Specification URL: https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR_028320.pdf

Resource Name: Zeiss Xradia 620 Versa X-ray microscope

Resource ID: SCR_028320

Alternate IDs: Model_Number_ZEISS_Xradia_620_Versa

Alternate URLs: <https://drexel.edu/core-facilities/facilities/material-characterization/our-instruments/xray-microscopy-tools>

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Ratings and Alerts

No rating or validation information has been found for Zeiss Xradia 620 Versa X-ray microscope.

No alerts have been found for Zeiss Xradia 620 Versa X-ray microscope.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.